

P-Channel 30-V (D-S) MOSFET

PRODUCT SUMMARY

V _{DS} (V)	R _{DS(on)} (Ω)	I _D (A) ^d	Q _g (Typ.)
- 30	0.011 at V _{GS} = - 10 V	- 13.5	29.5 nC
	0.015 at V _{GS} = - 4.5 V	- 11.6	

FEATURES

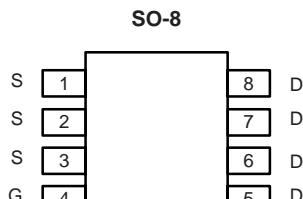
- Halogen-free
- TrenchFET® Power MOSFET
- 100 % R_g Tested
- 100 % UIS Tested



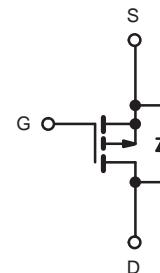
RoHS
COMPLIANT

APPLICATIONS

- Load Switch
- Notebook Adaptor Switch



Top View



P-Channel MOSFET

ABSOLUTE MAXIMUM RATINGS T_A = 25 °C, unless otherwise noted

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	- 30	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150 °C)	I _D	- 13.5	A
		- 11.9	
		- 10.9 ^{a, b}	
		- 8.6 ^{a, b}	
Pulsed Drain Current	I _{DM}	- 50	A
Continuous Source-Drain Diode Current	I _S	- 4.1	
		- 2.2 ^{a, b}	
Avalanche Current	I _{AS}	- 20	mJ
Single-Pulse Avalanche Energy	E _{AS}	20	
Maximum Power Dissipation	P _D	5.0	W
		3.2	
		2.7 ^{a, b}	
		1.7 ^{a, b}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS

Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{a, c}	R _{thJA}	38	46	°C/W
Maximum Junction-to-Foot	R _{thJF}	20	25	

Notes:

- Surface mounted on 1" x 1" FR4 board.
- t = 10 s.
- Maximum under Steady State conditions is 85 °C/W.
- Based on T_C = 25 °C.

SPECIFICATIONS $T_J = 25^\circ\text{C}$, unless otherwise noted

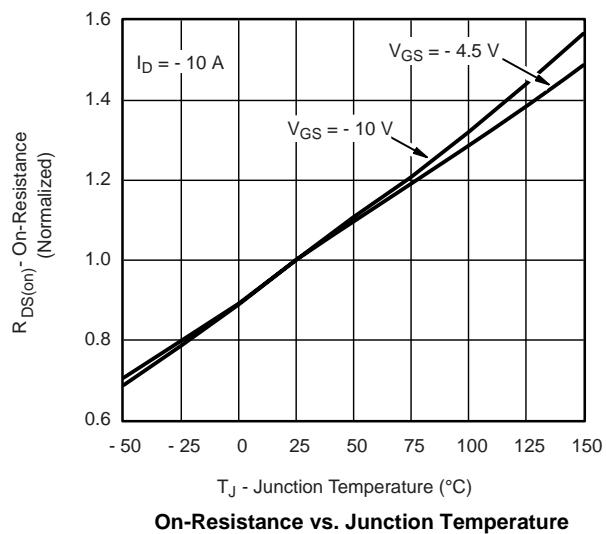
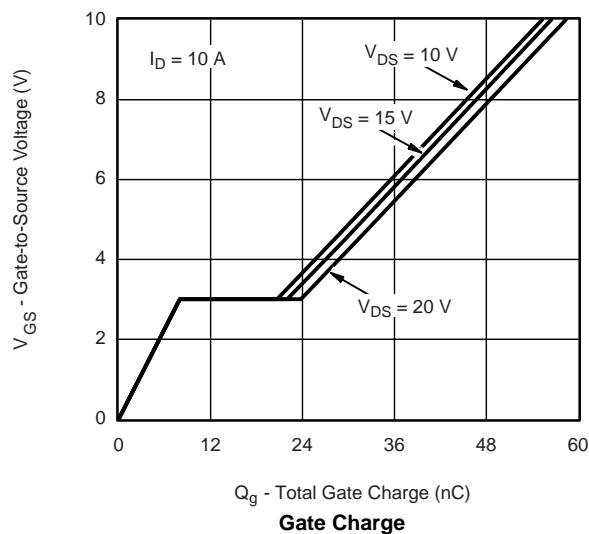
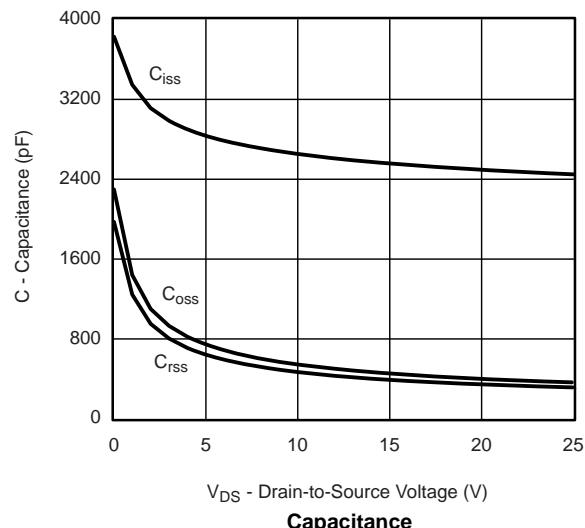
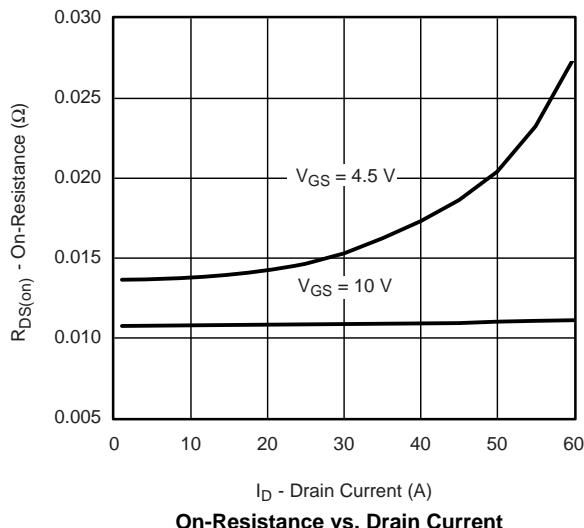
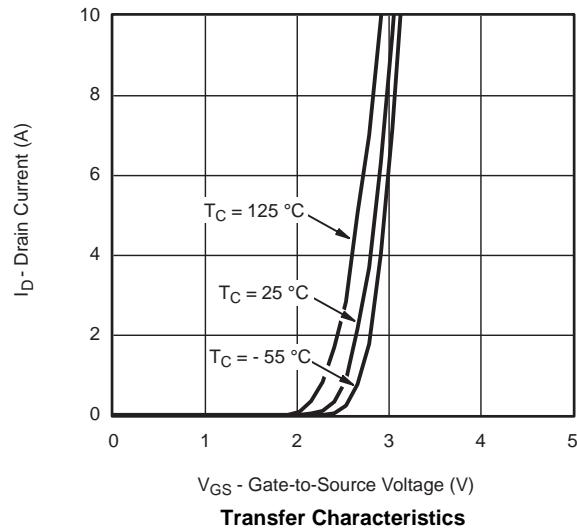
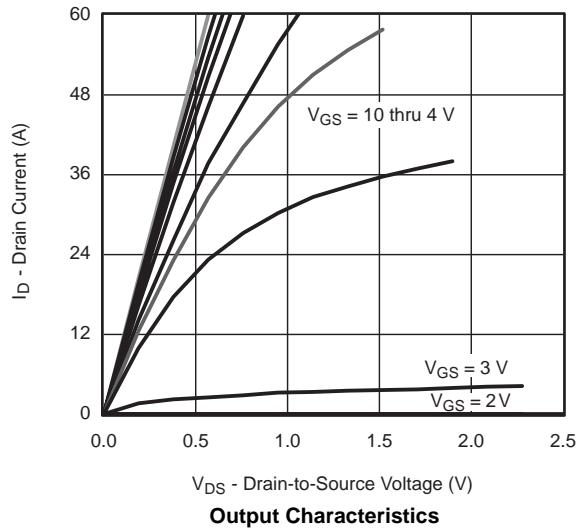
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit	
Static							
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	-30			V	
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = -250 \mu\text{A}$		-34			
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			5.3		mV/ $^\circ\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	-1.4		-2.5	V	
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			± 100	nA	
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}$			-1		
		$V_{DS} = -30 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			-5	μA	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \geq -10 \text{ V}, V_{GS} = -10 \text{ V}$	-30			A	
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = -10 \text{ V}, I_D = -10 \text{ A}$		0.011			
		$V_{GS} = -4.5 \text{ V}, I_D = -8 \text{ A}$		0.015		Ω	
Forward Transconductance ^a	g_{fs}	$V_{DS} = -10 \text{ V}, I_D = -10 \text{ A}$		28		S	
Dynamic^b							
Input Capacitance	C_{iss}	$V_{DS} = -15 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		2550			
Output Capacitance	C_{oss}			455			
Reverse Transfer Capacitance	C_{rss}			390		pF	
Total Gate Charge	Q_g	$V_{DS} = -15 \text{ V}, V_{GS} = -10 \text{ V}, I_D = -10 \text{ A}$		57	86	nC	
Gate-Source Charge	Q_{gs}	$V_{DS} = -15 \text{ V}, V_{GS} = -4.5 \text{ V}, I_D = -10 \text{ A}$		29.5	45		
Gate-Drain Charge	Q_{gd}			8			
Gate Resistance	R_g			22			
Turn-On Delay Time	$t_{d(\text{on})}$	$V_{DD} = -15 \text{ V}, R_L = 1.5 \Omega$ $I_D \geq -10 \text{ A}, V_{GEN} = -10 \text{ V}, R_g = 1 \Omega$		0.5	2.2	4.4	Ω
Rise Time	t_r			13	25	ns	
Turn-Off DelayTime	$t_{d(\text{off})}$			12	24		
Fall Time	t_f			40	70		
Turn-On Delay Time	$t_{d(\text{on})}$			9	18		
Rise Time	t_r	$V_{DD} = -15 \text{ V}, R_L = 1.5 \Omega$ $I_D \geq -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		48	80	ns	
Turn-Off DelayTime	$t_{d(\text{off})}$			92	160		
Fall Time	t_f			34	60		
				19	35		
Drain-Source Body Diode Characteristics							
Continous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			-4.1	A	
Pulse Diode Forward Current	I_{SM}				-60		
Body Diode Voltage	V_{SD}	$I_S = -3 \text{ A}, V_{GS} = 0 \text{ V}$		-0.75	-1.2	V	
Body Diode Reverse Recovery Time	t_{rr}	$I_F = -10 \text{ A}, dI/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		27	45	ns	
Body Diode Reverse Recovery Charge	Q_{rr}			16	27	nC	
Reverse Recovery Fall Time	t_a			12		ns	
Reverse Recovery Rise Time	t_b			15			

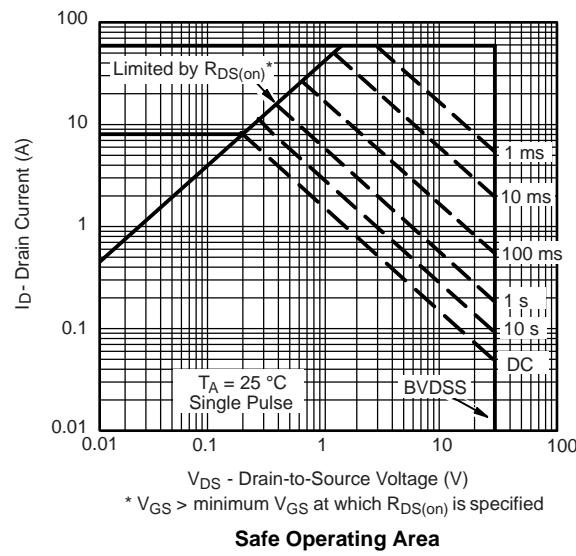
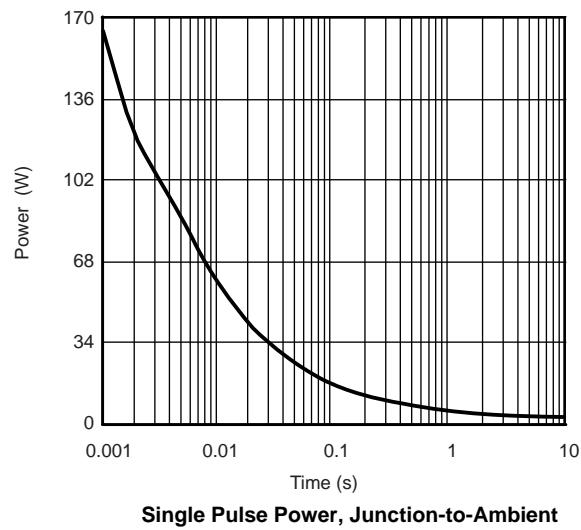
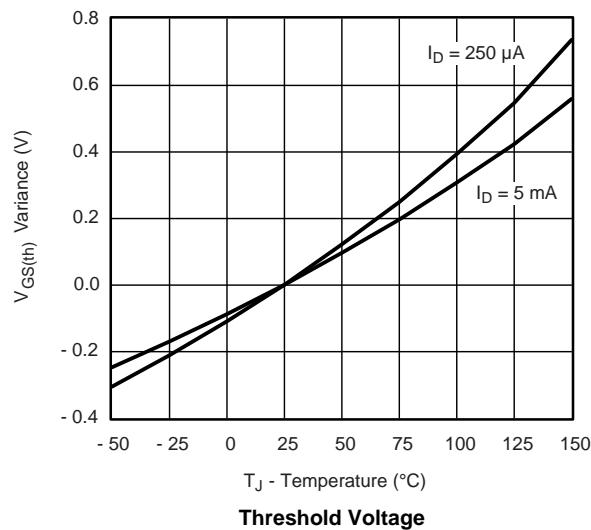
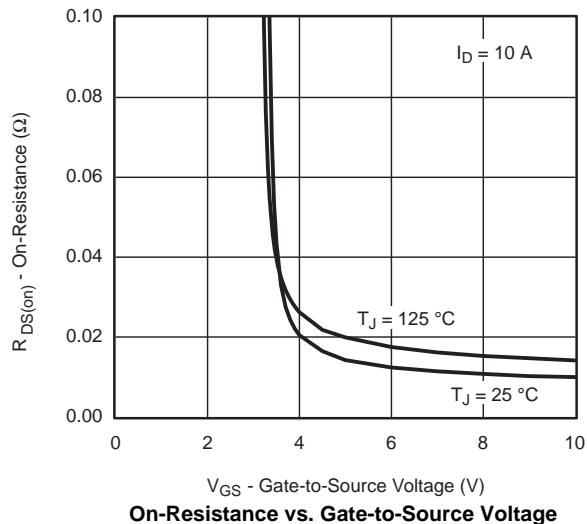
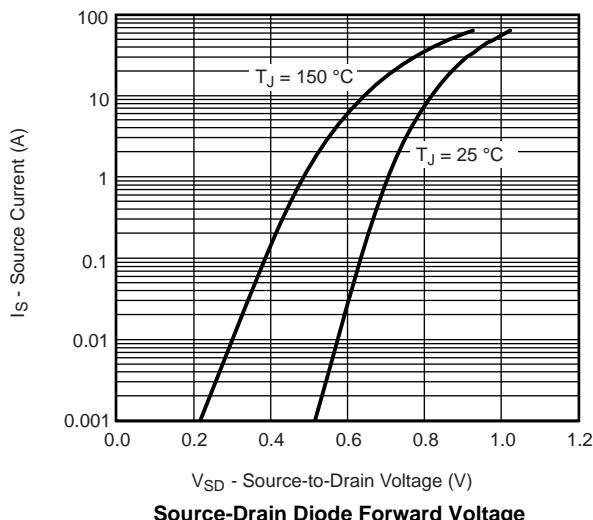
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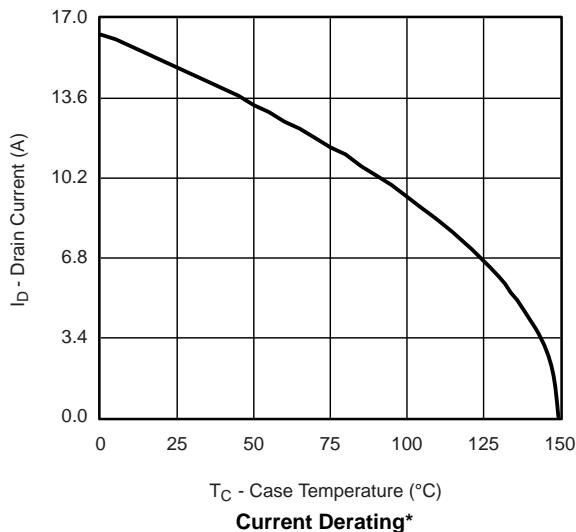
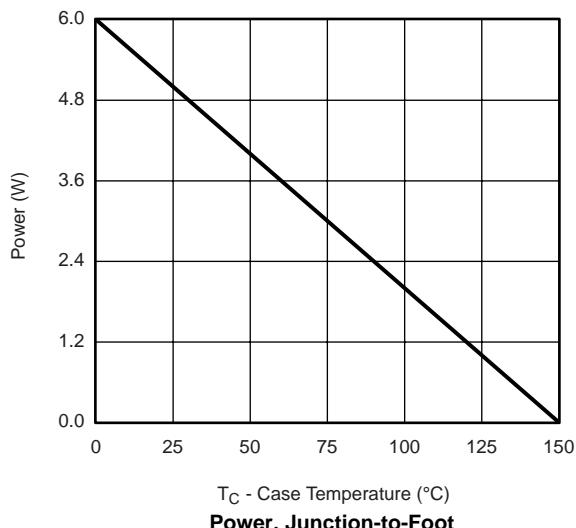
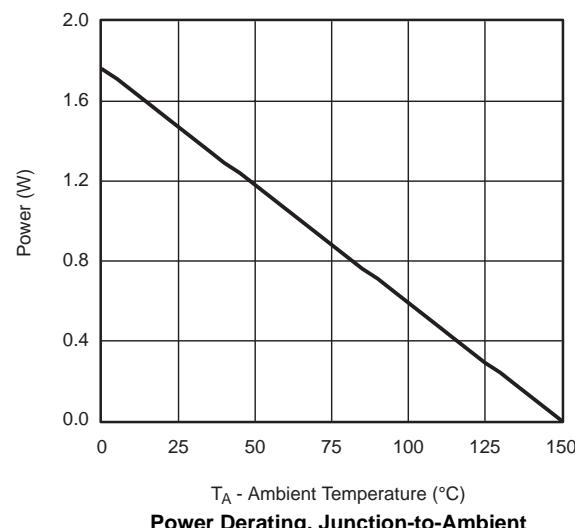
a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$.

b. Guaranteed by design, not subject to production testing.

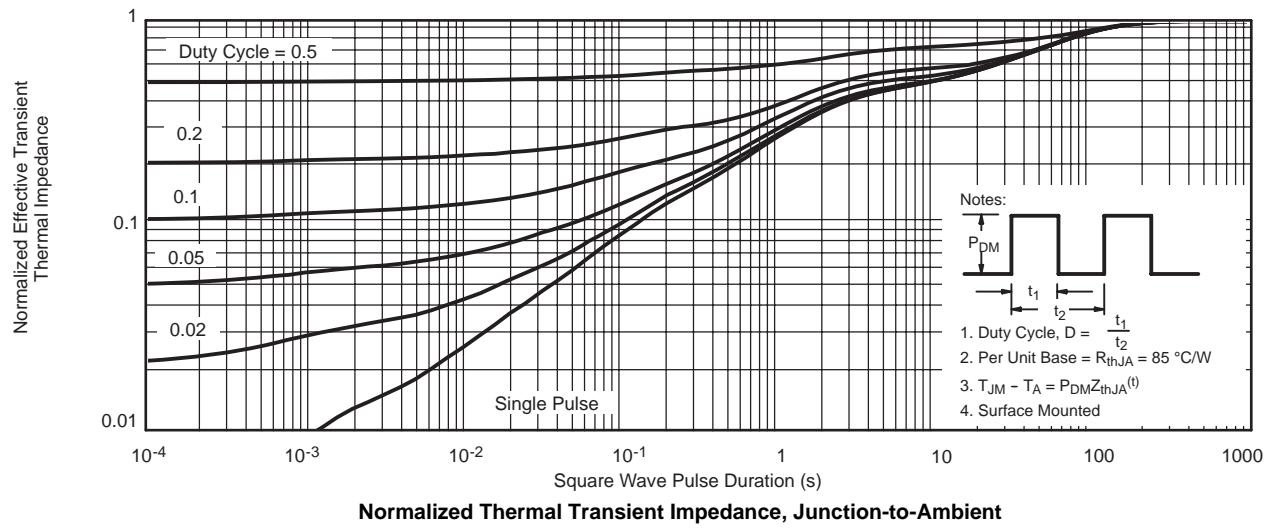
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

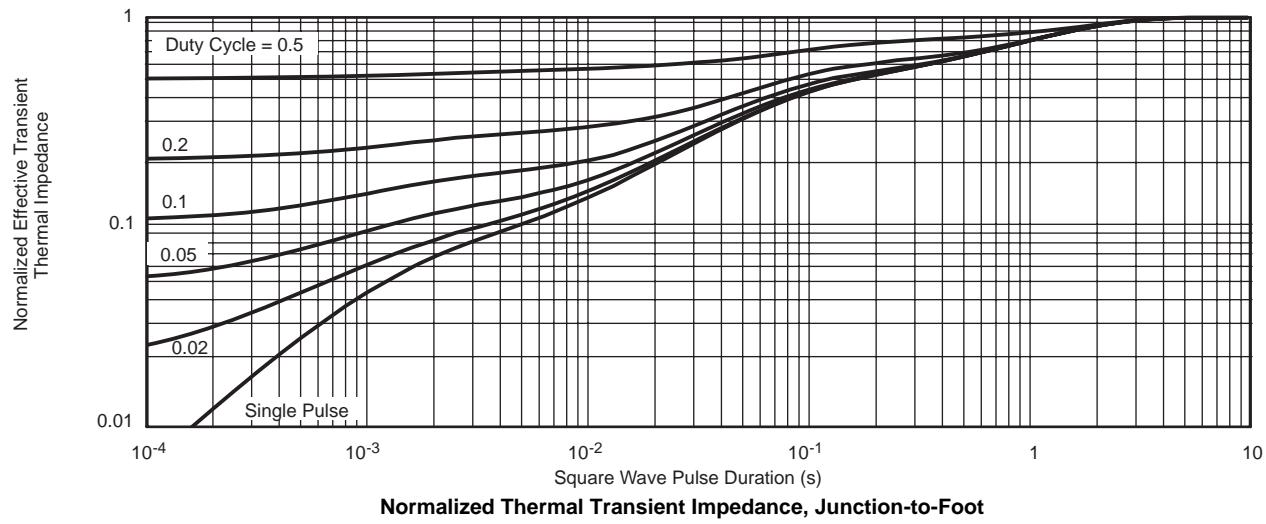
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MOSFET TYPICAL CHARACTERISTICS 25 °C, unless otherwise notedT_C - Case Temperature (°C)**Current Derating***T_C - Case Temperature (°C)**Power, Junction-to-Foot**T_A - Ambient Temperature (°C)**Power Derating, Junction-to-Ambient**

* The power dissipation P_D is based on T_{J(max)} = 150 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted

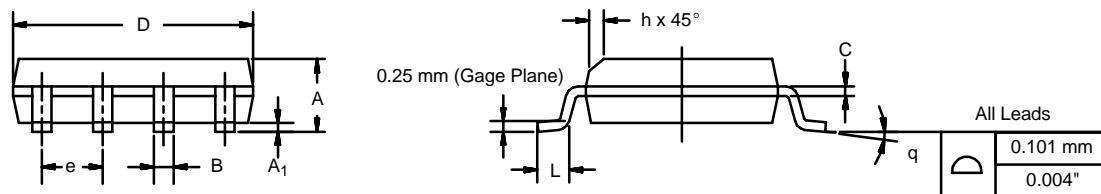
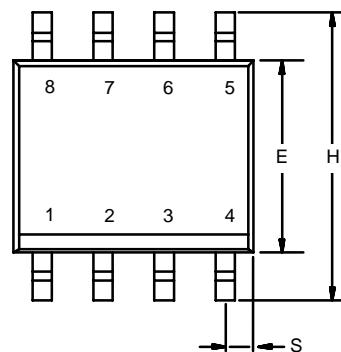
Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot

SOIC (NARROW): 8-LEAD

JEDEC Part Number: MS-012



DIM	MILLIMETERS		INCHES	
	Min	Max	Min	Max
A	1.35	1.75	0.053	0.069
A ₁	0.10	0.20	0.004	0.008
B	0.35	0.51	0.014	0.020
C	0.19	0.25	0.0075	0.010
D	4.80	5.00	0.189	0.196
E	3.80	4.00	0.150	0.157
e	1.27 BSC		0.050 BSC	
H	5.80	6.20	0.228	0.244
h	0.25	0.50	0.010	0.020
L	0.50	0.93	0.020	0.037
q	0°	8°	0°	8°
S	0.44	0.64	0.018	0.026

ECN: C-06527-Rev. I, 11-Sep-06
DWG: 5498

RECOMMENDED MINIMUM PADS FOR SO-8

